

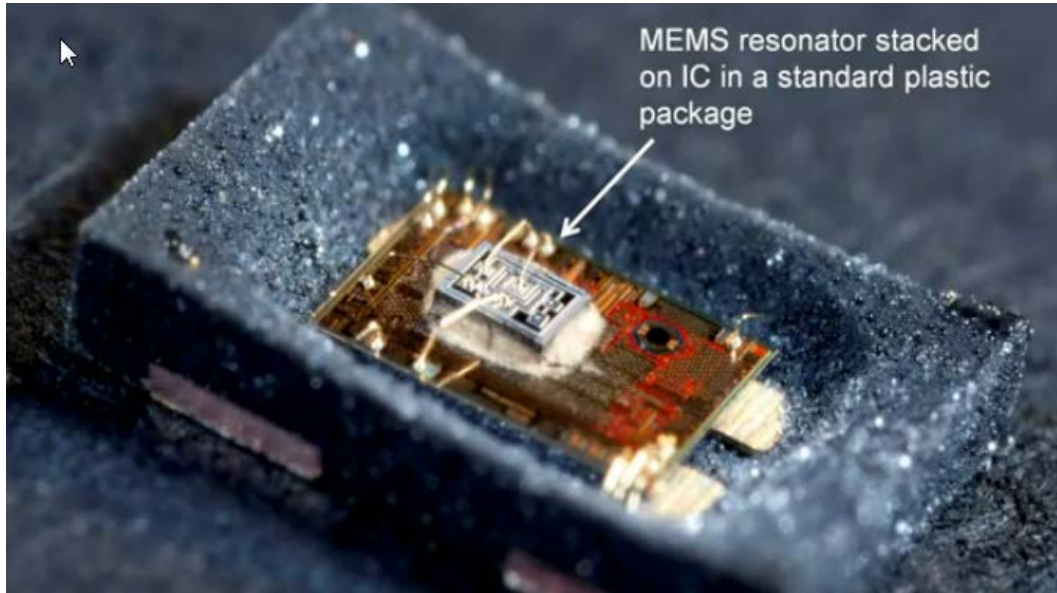


## MEMS resonator

Presentation by

Drs. Helger van Halewijn

# MEMS resonator overview package



- Resonator size 500 x 700 x 150 micron
- Single silicon on CMOS technology
- High frequency stability, low time jitter, low temperature drift.
- Low motion damping → Q-factor > 40000 ( $\approx$  50 MHz)

# Overview of dogbone resonator

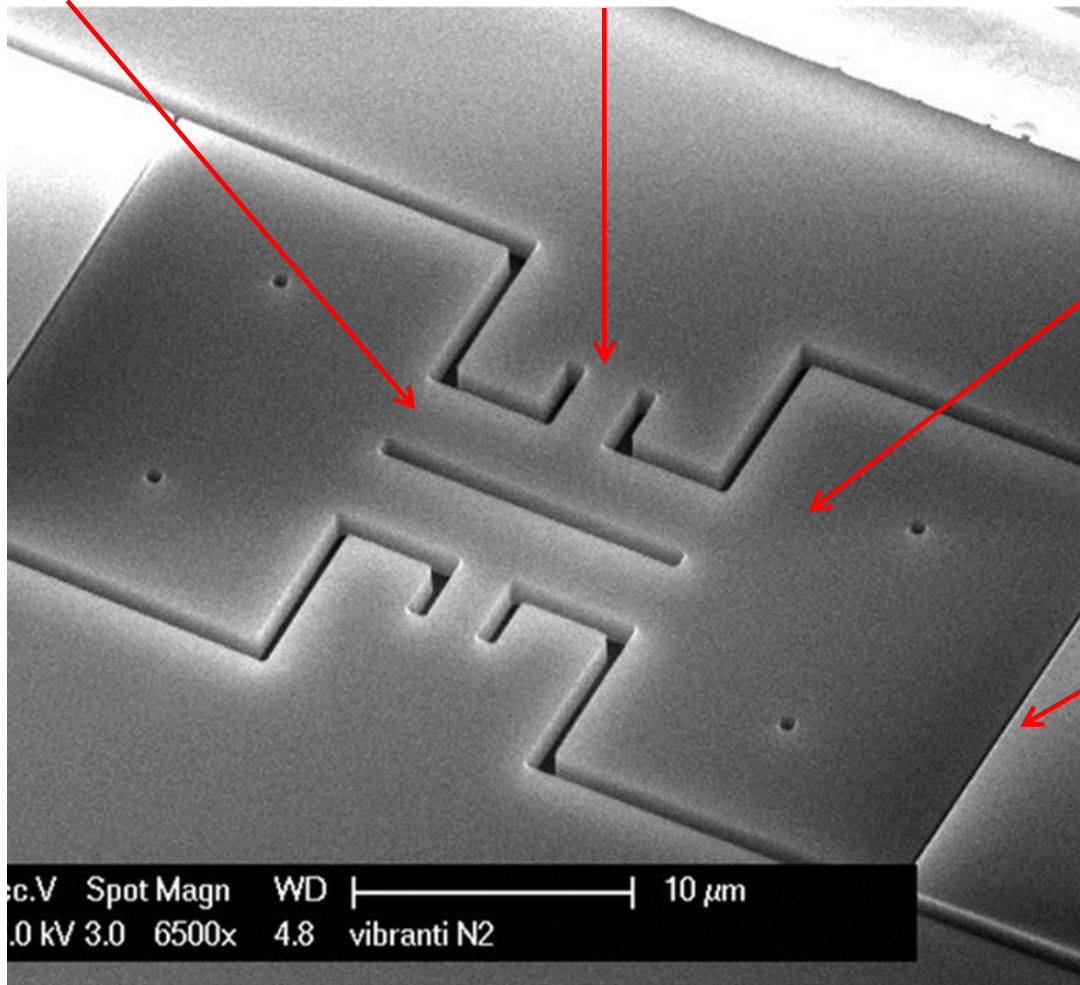


spring

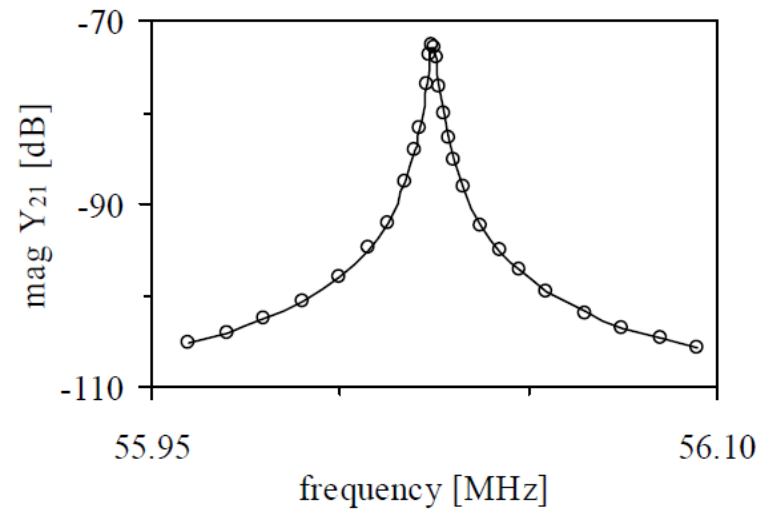
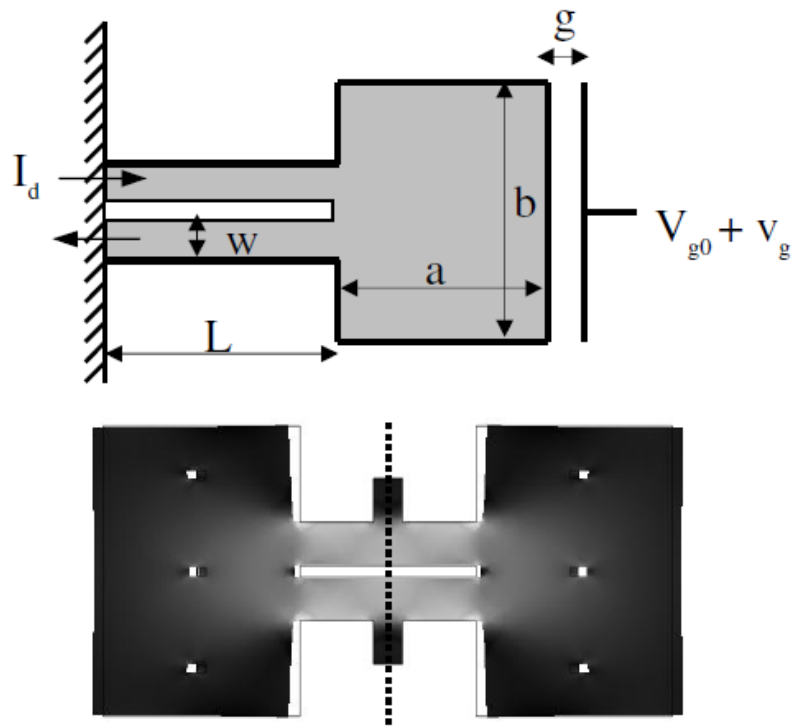
anchor

“mass” of resonator

actuation gap



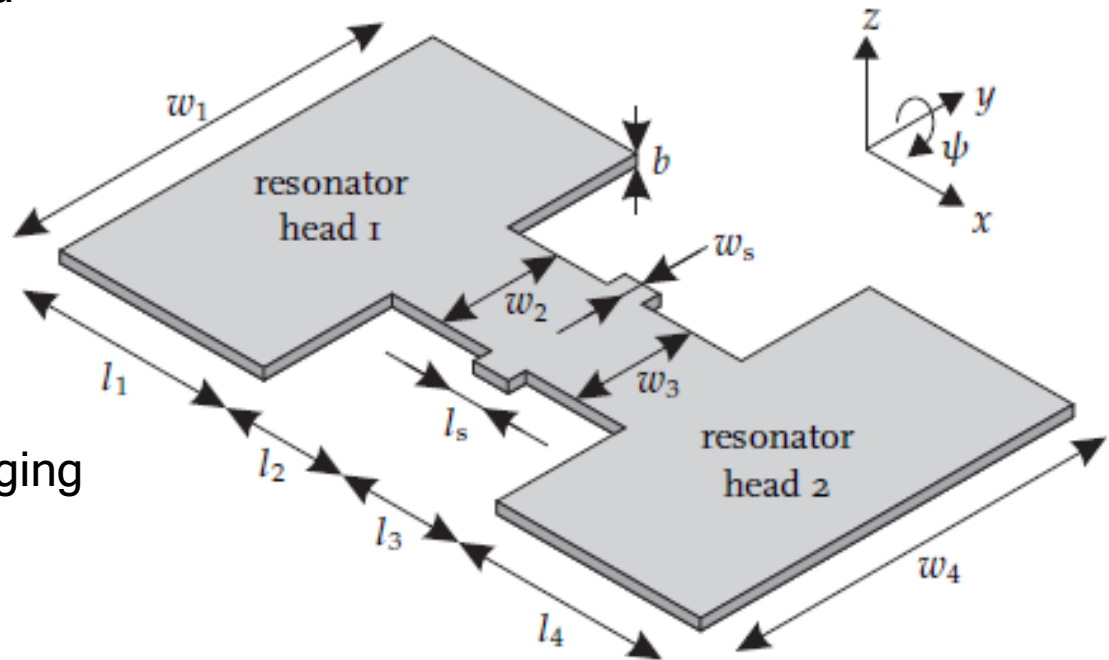
# Schematic of dogbone resonator



# Some parameters studied in COMSOL



- During production in waferfab all dimensions variations can influence the performance
- Q-factor, resonance stability
  1. Dimensions resonator head
  2. Anchor loss
  3. Thickness Si
  4. Oxidation layer
  5. Air pressure (vacuum)\
  6. Thermal losses.
  7. Viscous Drag
  8. Electrostatic actuation+fringing
  9. Mode coupling.



# Non linear resonance frequency

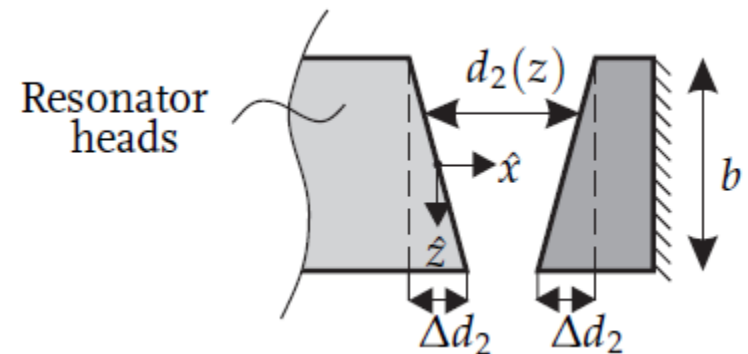
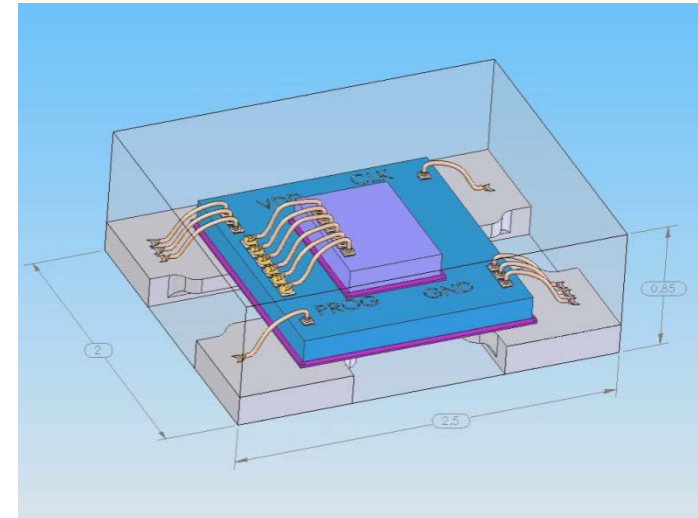


- Resonance frequency

$$F_{el} = \eta V_{AC} \sin(\omega t) + \frac{V_{DC} \eta x}{g}$$

$$f_{res} = \sqrt{\frac{k}{m} - \frac{V_{DC}^2 \epsilon_0 w h}{m g^3}}$$

1. k spring constant
2. m mass system
3. V driving voltage
4. w width
5. h height
6. g gap



# Q-factor estimation

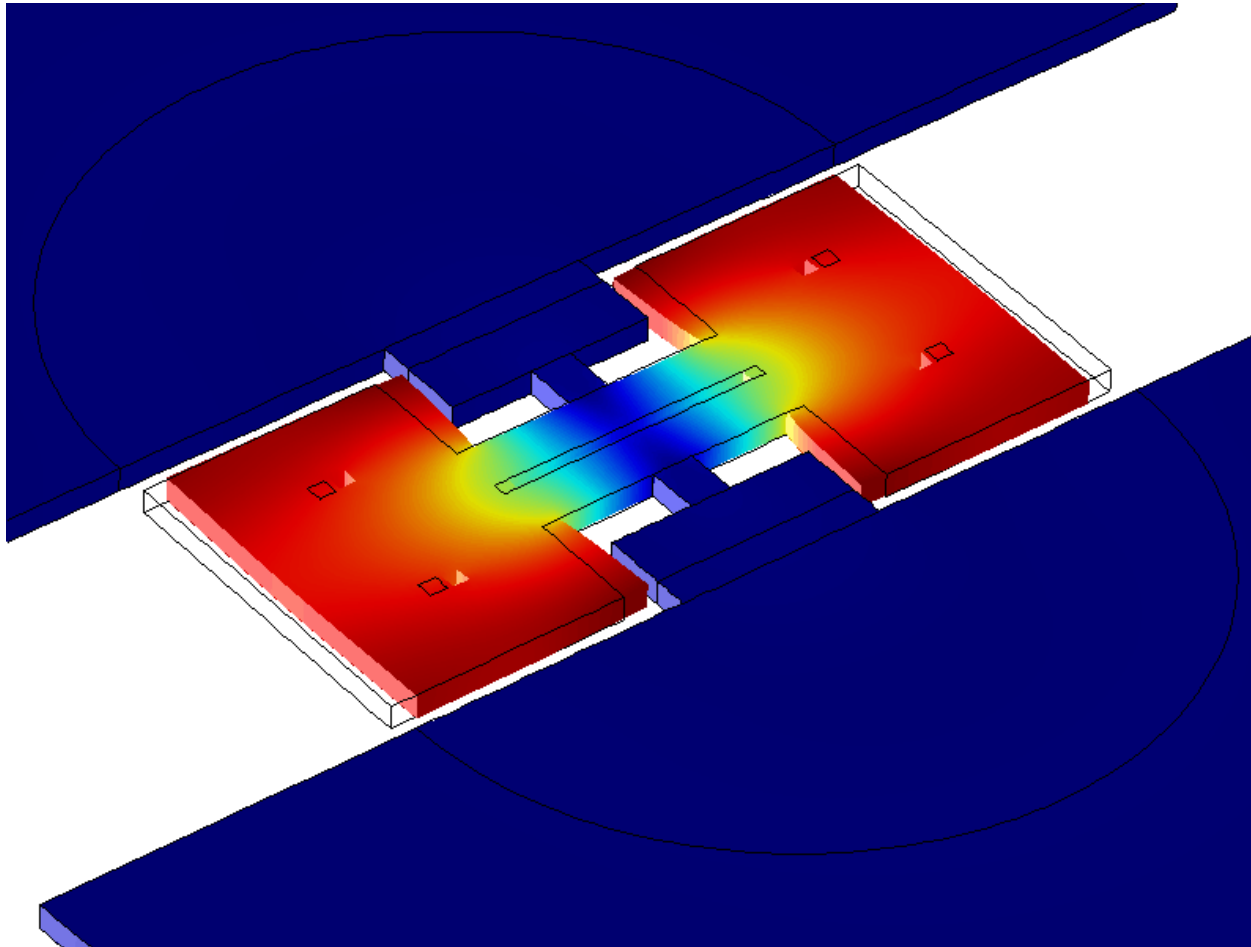


- Reciprocal addition.

$$\frac{1}{Q_{tot}} = \sum_{i=1}^N \frac{1}{Q_i}$$

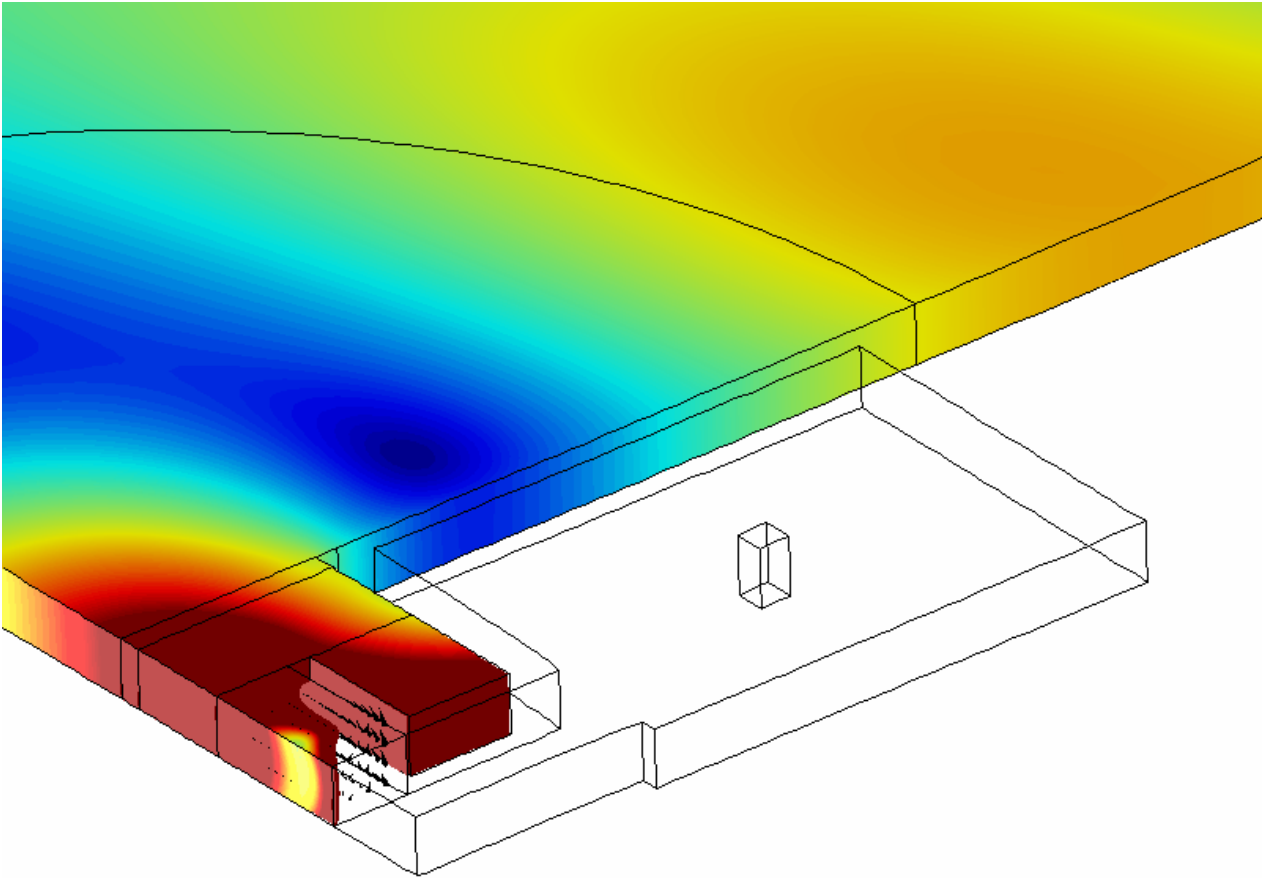
- Anchor loss :  $Q_{anchor} \approx 10^4 - 10^7$  dimension
- Thermo-elastic loss  $Q_{te} \approx 10^4 - 10^6$  material
- Surface loss:  $Q_{sur} \approx 10^6 - 10^8$  debris or cracks
- Air damping:  $Q_{air} \approx 10^2 - 10^7$  vacuum quality, leakage
- Viscous drag  $Q_{drag} \approx 10^5 - 10^7$  vacuum quality
  
- All separate Q factors are estimated with COMSOL.

# Overview resonance mode at 56 MHz

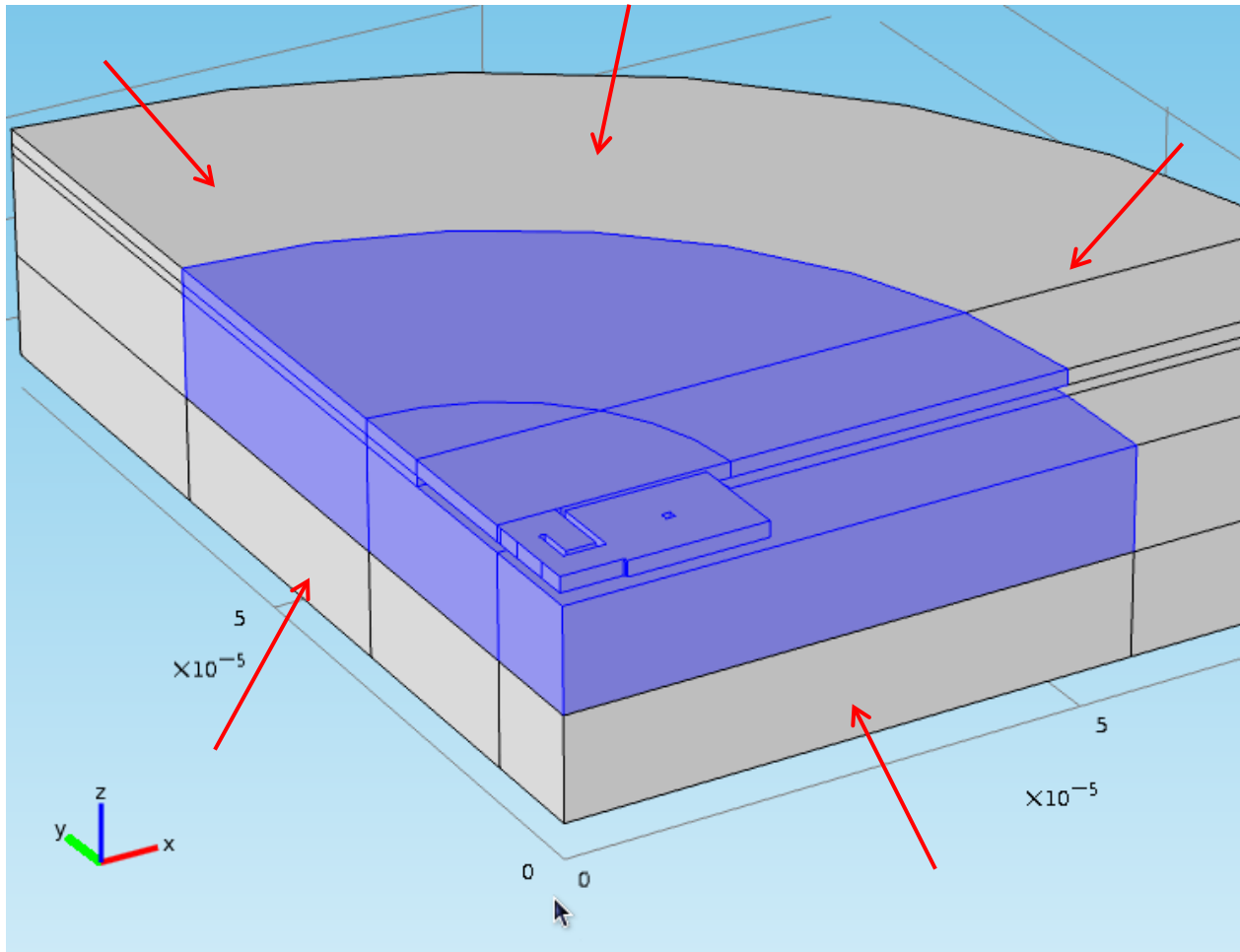




# Acoustic loss at anchor.

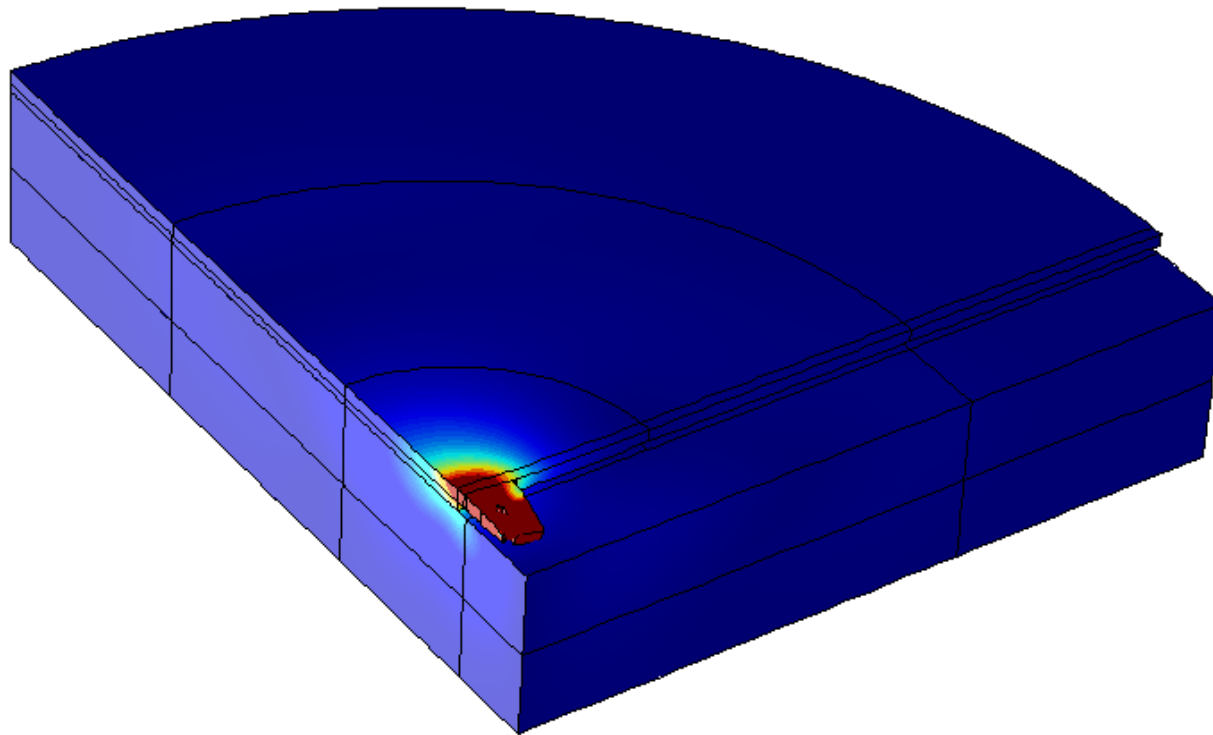


# Acoustic loss: Gray domains, PML



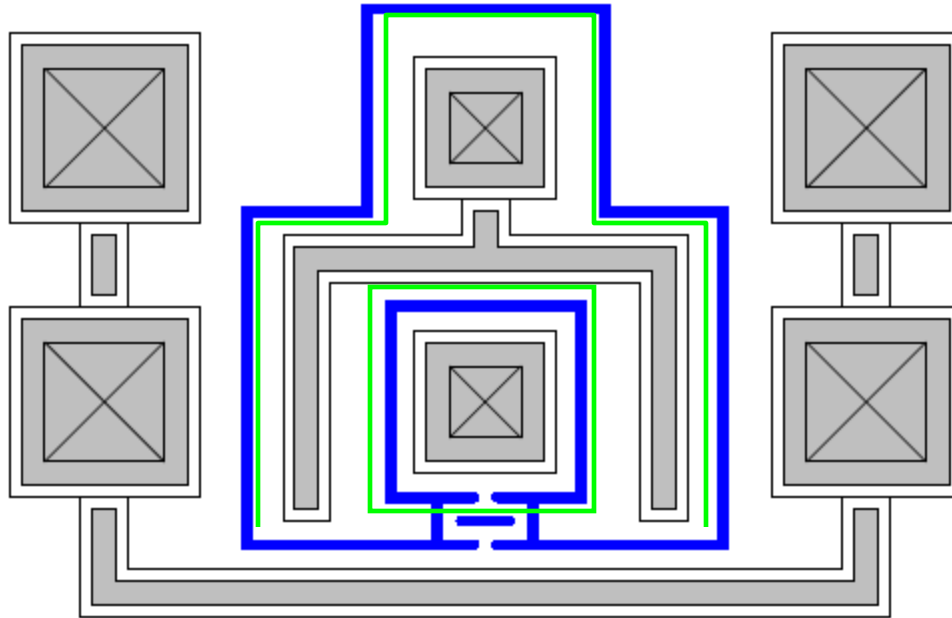
- Red arrows indicate PML-layers.
- In PML complete acoustic absorption.
- Blue domains represent normal material properties.
- Eigenfrequency analyses.

# Acoustic loss: dimensional variations in the structure.

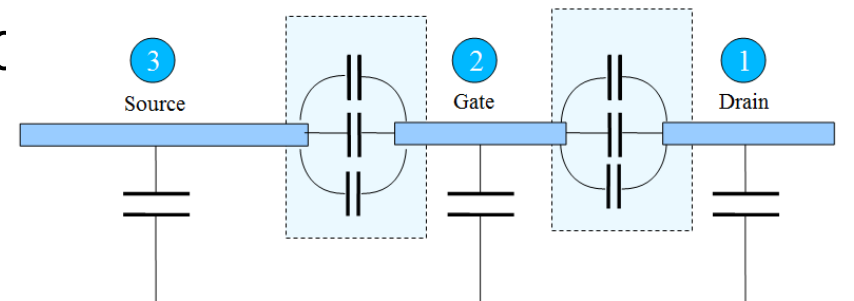


# Capacitances

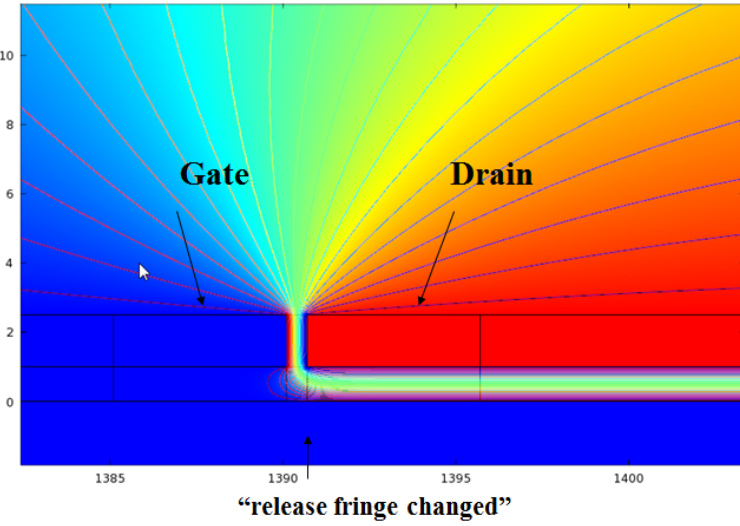
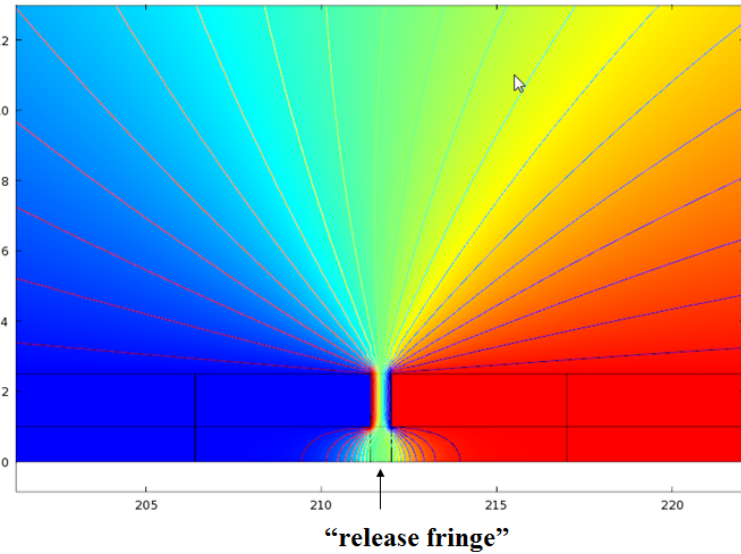
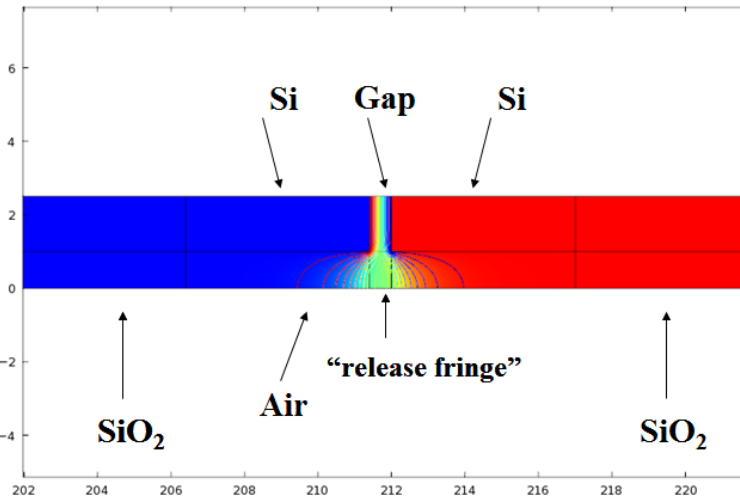
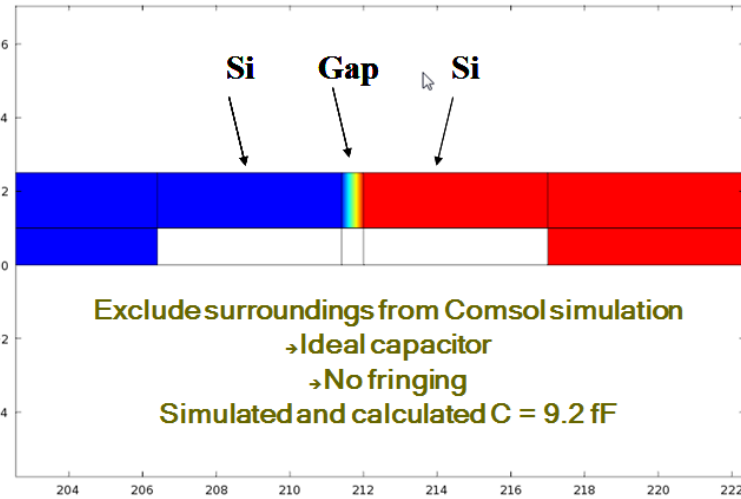
## Present design



- Area of gate within green lines is  $410 \mu\text{m}^2$



# Fringe effects, from simple to real system



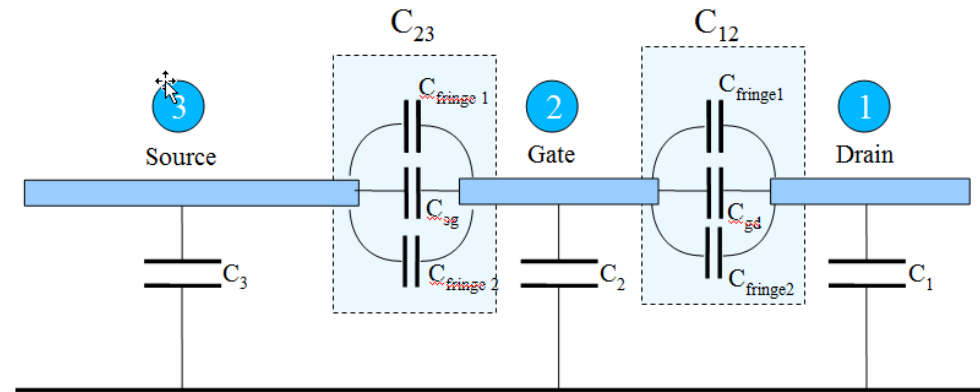
- Simulated Cap = 338 fF
- Dominated by drain bottom capacitance

# Calculation + Simulation Gate Capacitance



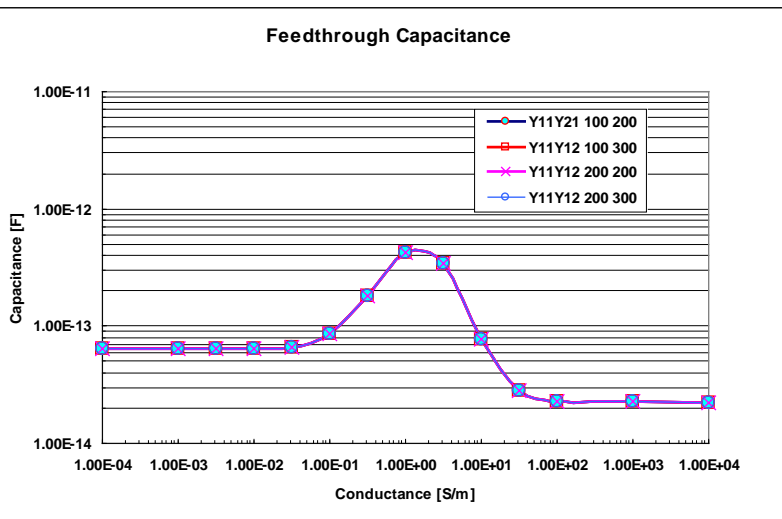
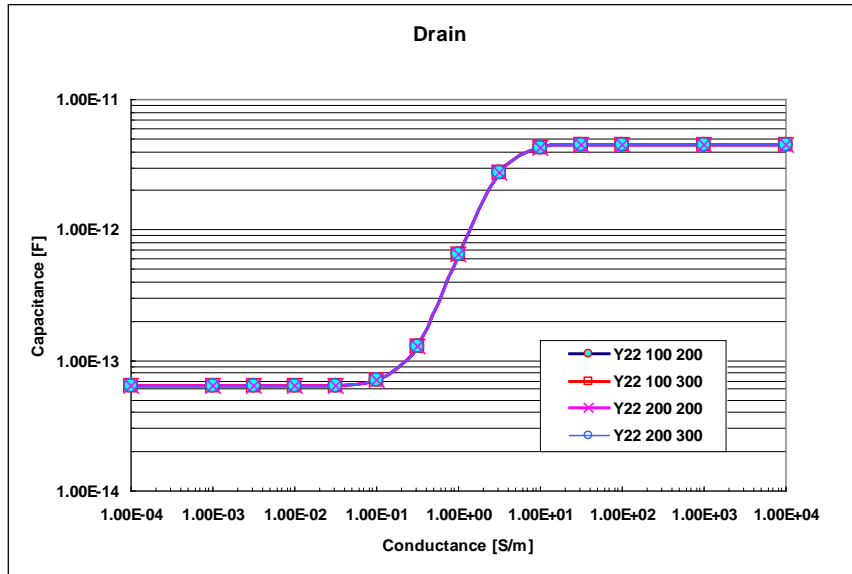
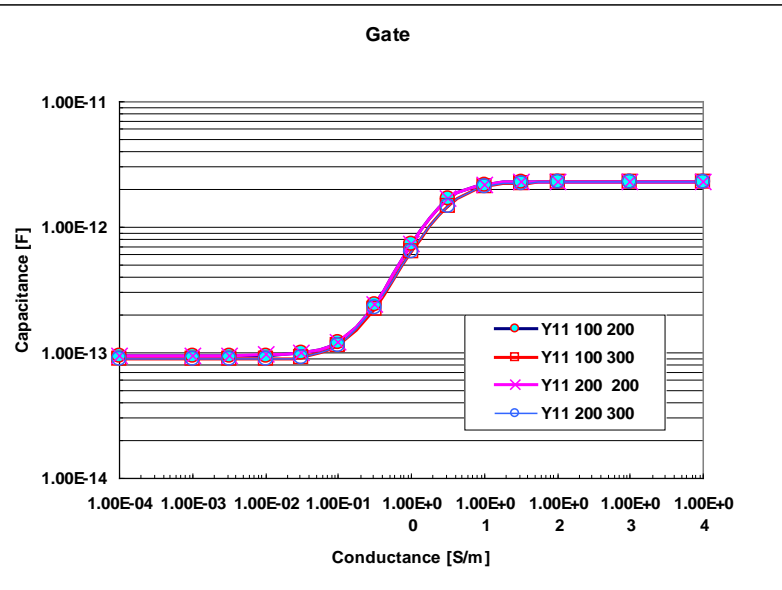
1. Simple hand calculation Drain  $C_1 = 322$  fF
2. Gate  $C_2 = 1270$  fF and Source  $C_3 = 18700$  fF
3. Capacitance  $C_{12} = 22.5$  fF and  $C_{23} = 51$  fF
4. Using mathematical formula

$$C_{gate} = C_{12} + C_{23} + \frac{1}{\frac{1}{C_2} + \frac{1}{C_1 + C_3}}$$



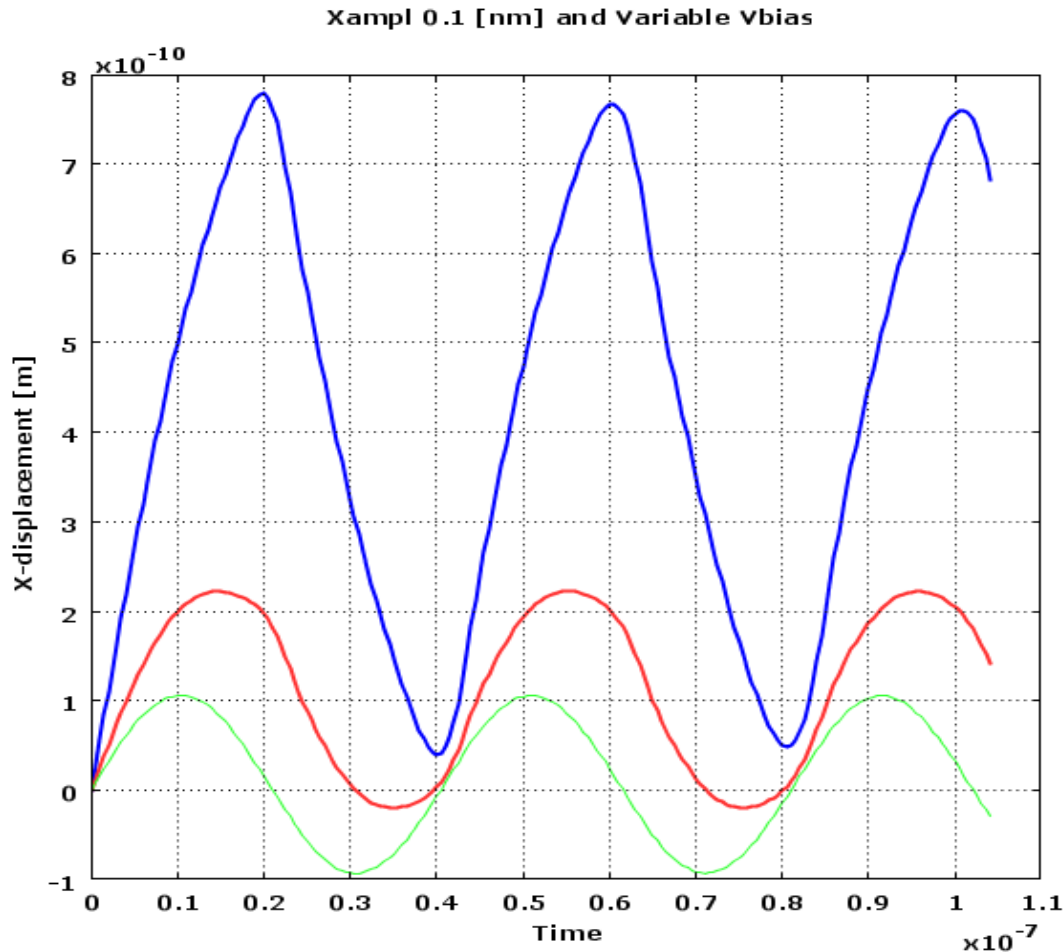
5.  $C_{gate} = 1264$  fF
6. Comsol result is  $C_{gate\ Comsol} = 1266$  fF  $\rightarrow$  OK
7.  $C_{source}$  and  $C_{drain}$  have similar accuracies.

# Capacitance as function of resistivity



1. Results from Comsol
2. Including effects like air height and substrates thickness
3. Resonator operates at 0.3 - 1.2  $\Omega\text{cm}$  (equivalent to 80 - 330 S/m)
4. Capacitance variation is  $< 2\%$  in resistivity range
5. All simulations are performed with 56 MHz

# Asymmetric amplitude under electrical load (V bias)



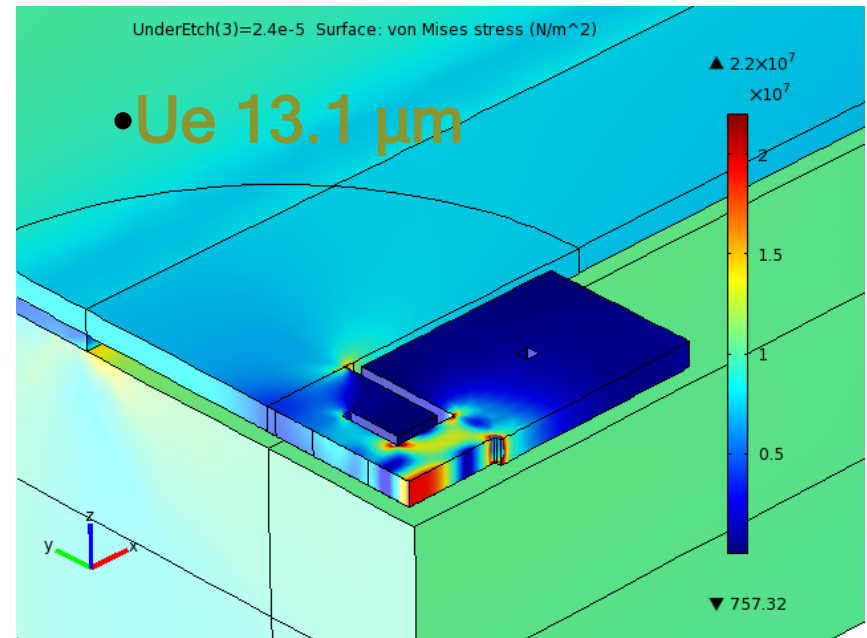
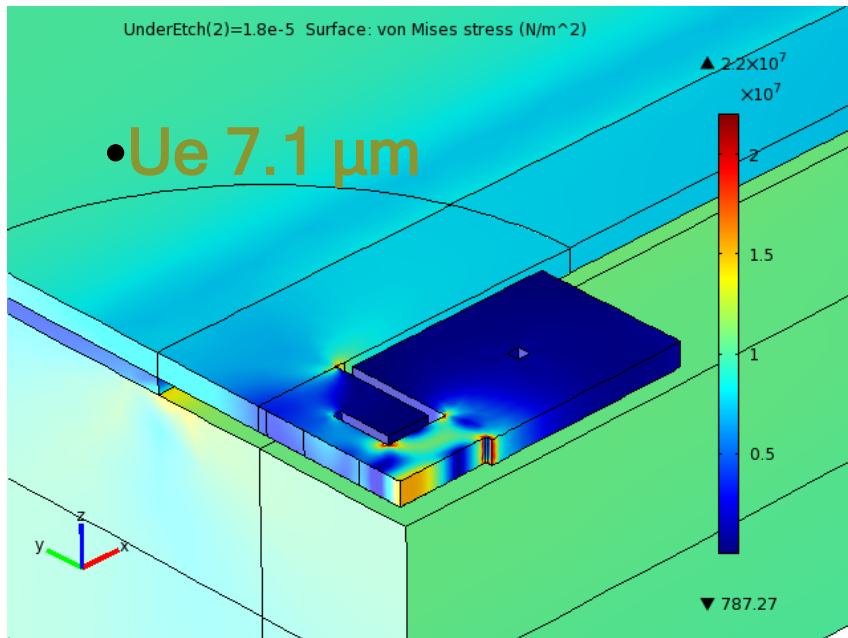
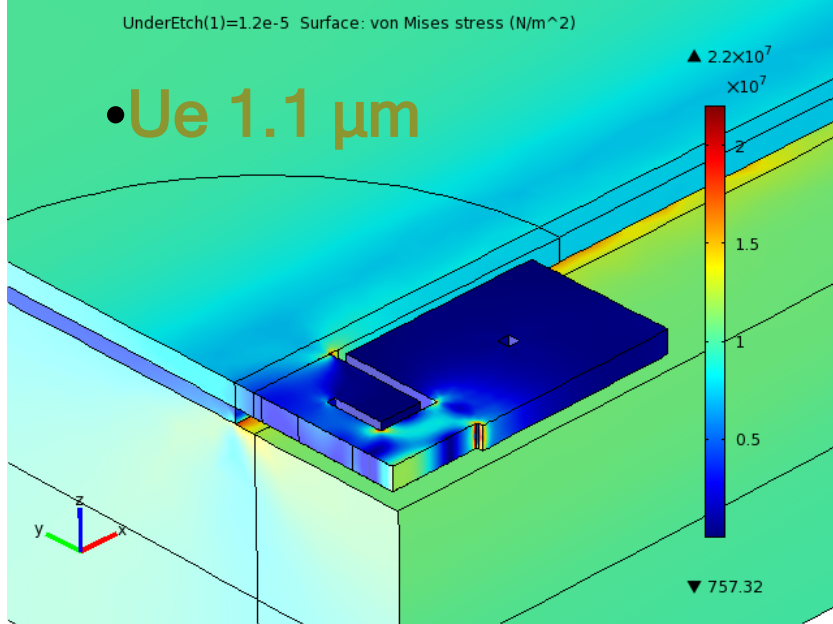
- At 10 Volt, a harmonic behavior.
- At 80 Volt bias an inharmonic term can easily be seen.
- At 56 MHz, oscillation time is 40 nsec.
- COMSOL time step < 1 nsec





# Static stress due to process cycles

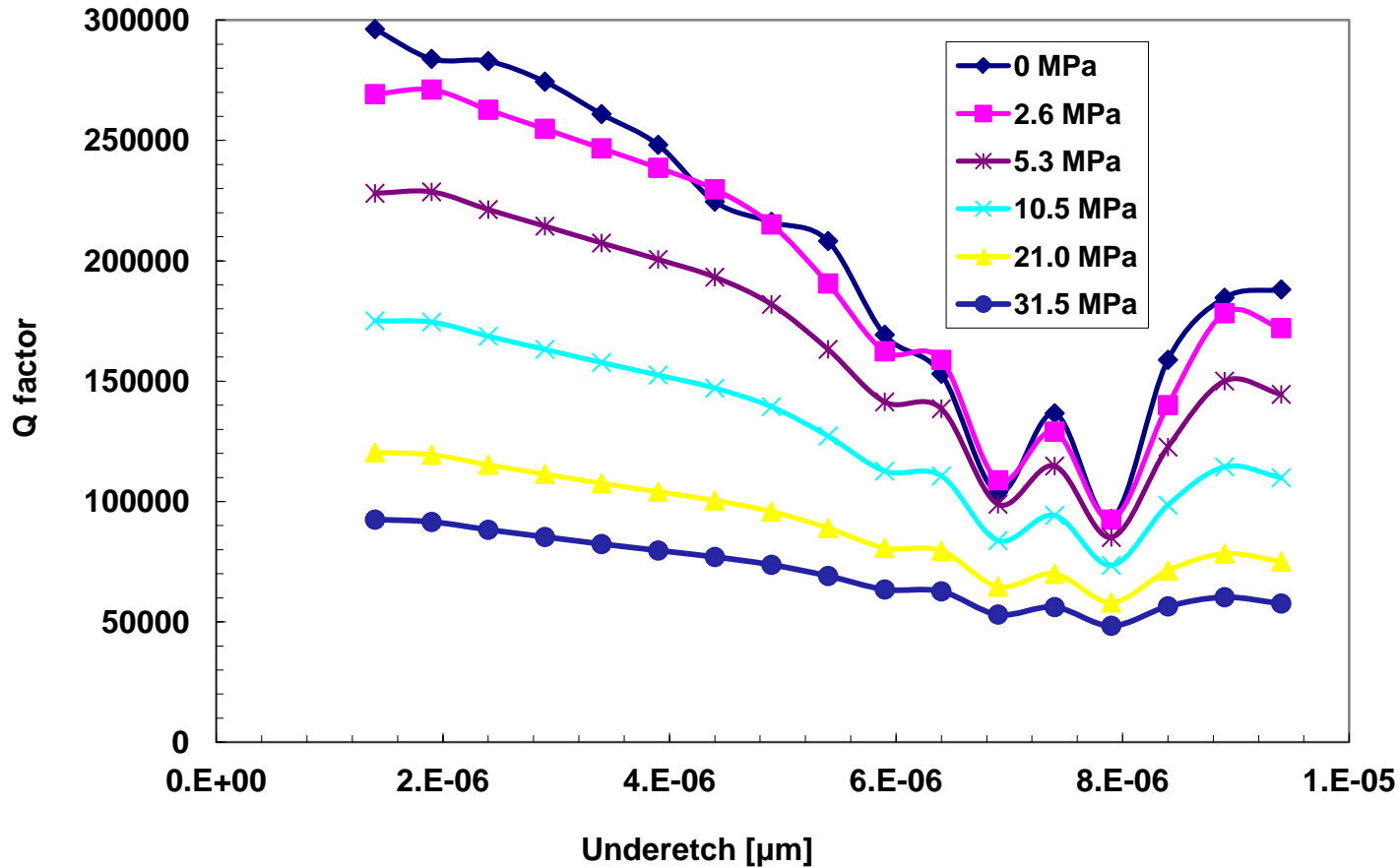
- Static stress at periphery due to curing procedures at various process conditions
- Stress concentrations in resonator legs.



# Q-factor of resonator under Stress



Q-factor as function of Underetch and Stress



# Thermal losses in resonator

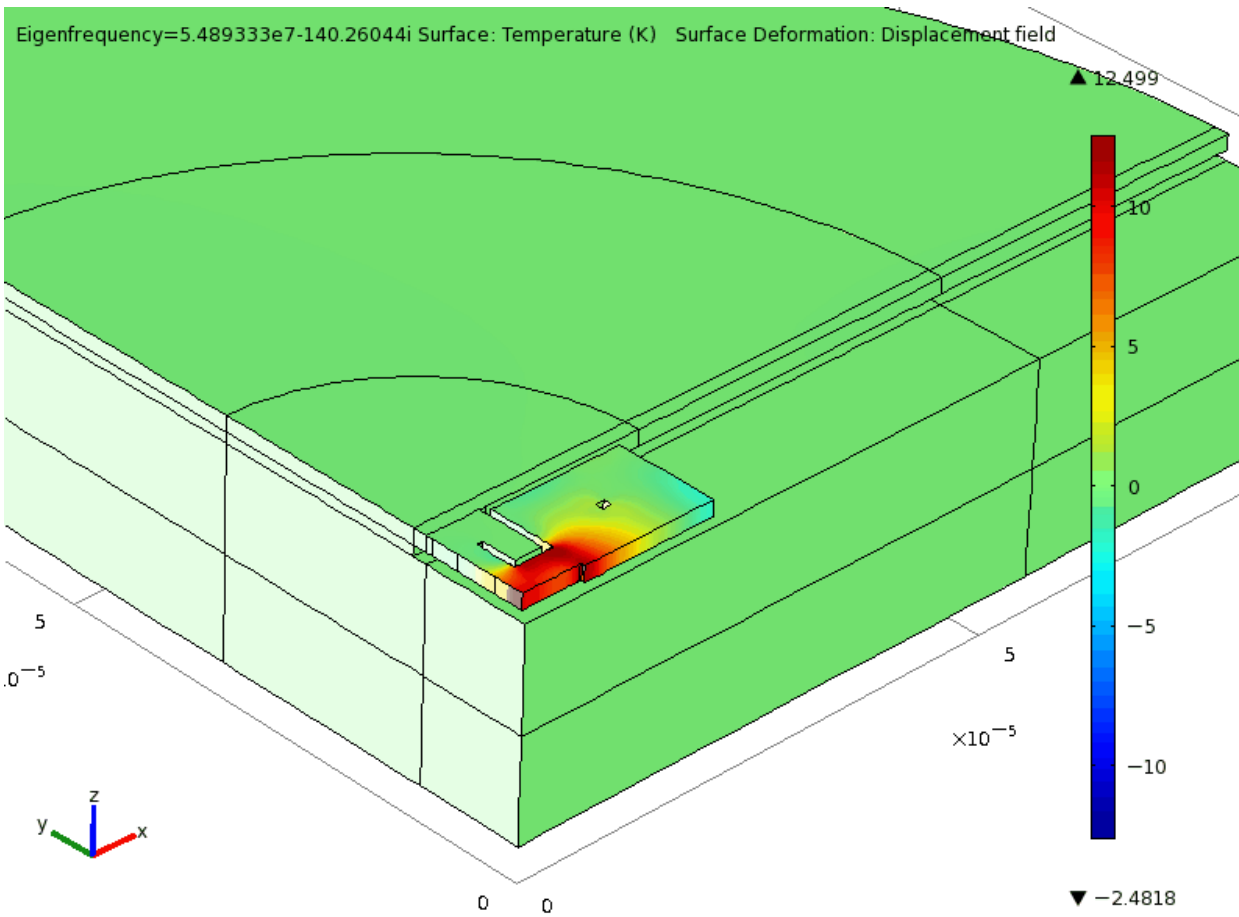


- Q-factor can be written as:

$$\frac{1}{Q_{therm}} = \frac{E\alpha^2 T_o}{\rho C_p} \frac{\omega\tau}{1 + (\omega\tau)^2}$$

- E = Youngs Modulus [Pa]
- $\alpha$  = expansioncoefficient [1/m]
- $T_o$  = ambient temperature [K]
- $\rho$  = density [kg/m<sup>3</sup>]
- $\omega$  = frequency [rad/s]
- $\tau$  = thermal relaxation [s]

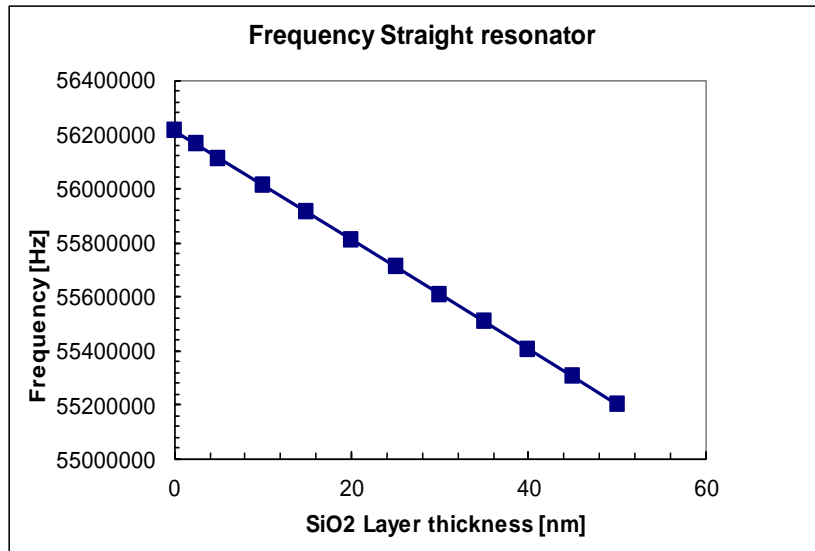
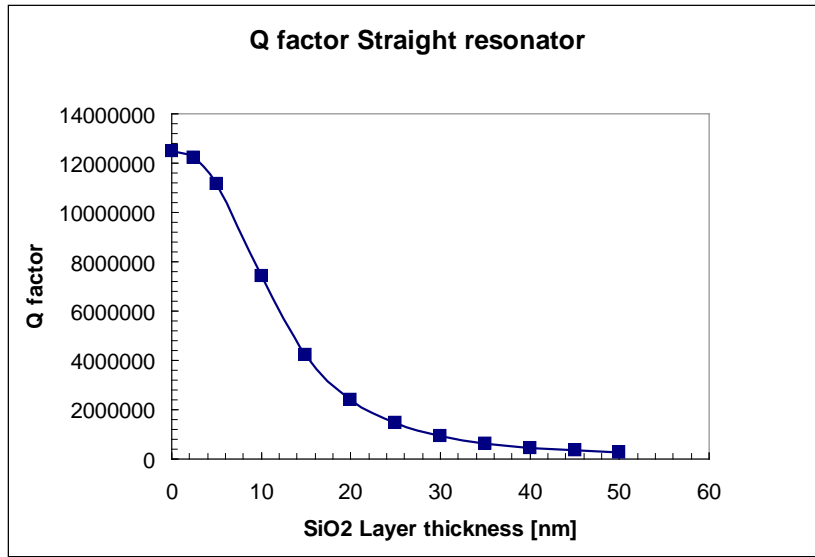
# Thermal losses in resonator



Temperature fluctuations of about  $\pm 10^{\circ}\text{C}$ , at 56 MHz.

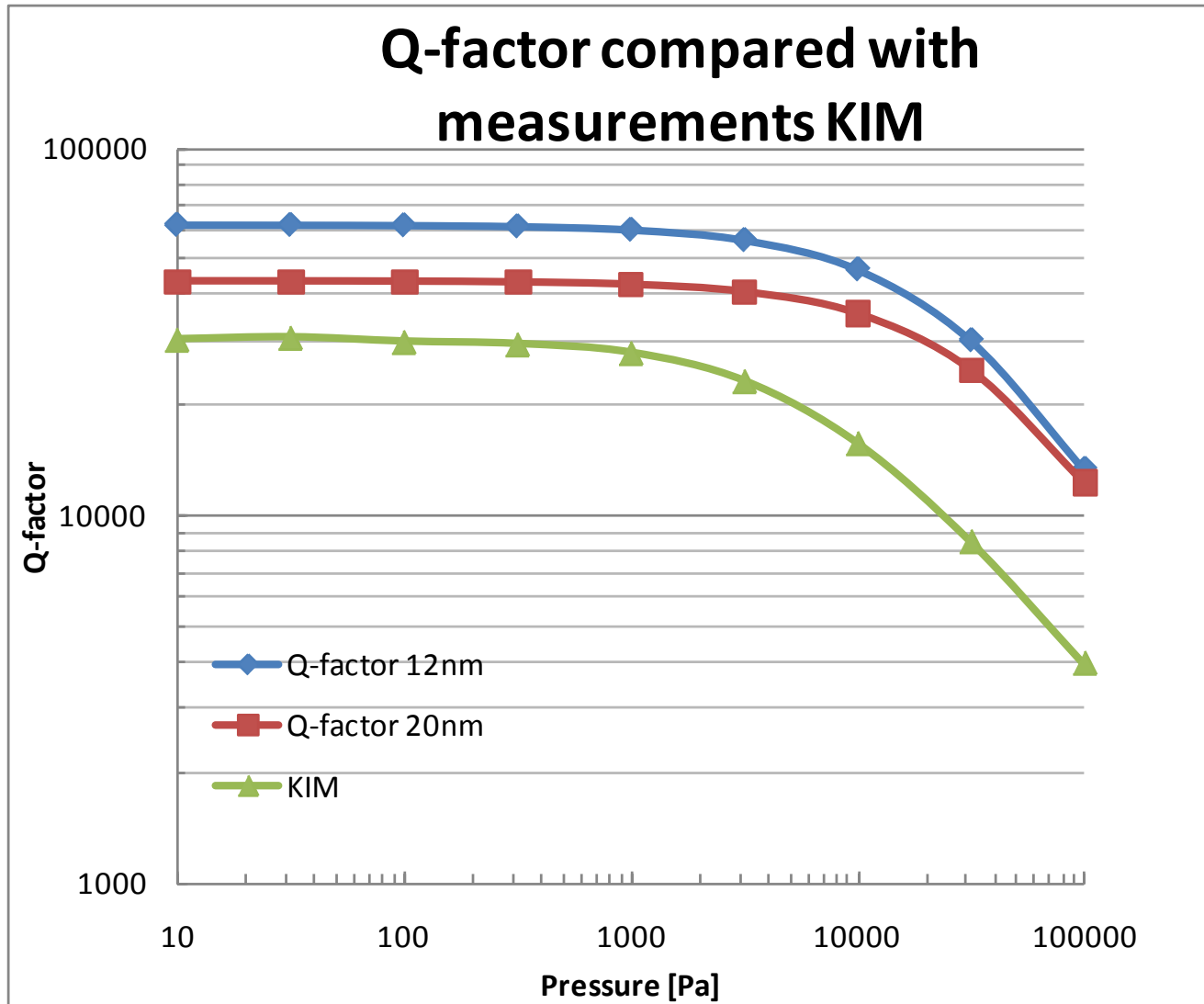
This mechanism is due to material properties.

# Thickness Oxidation: Q factor and frequency shift



- Simulation with single layer.
- Mesh is adapted at layers lower than 20 nm.
- Minimum layer thickness 2.5 nm.
  
- In Comsol, Solid mechanics and shells are combined.

# Squeezed film effect including stress

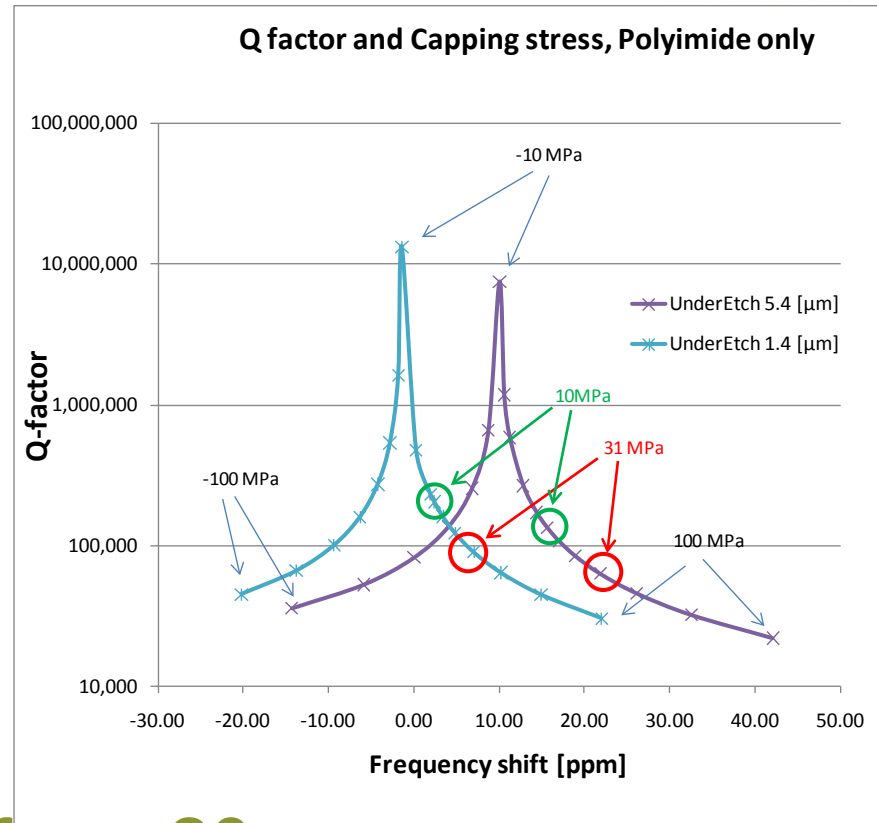
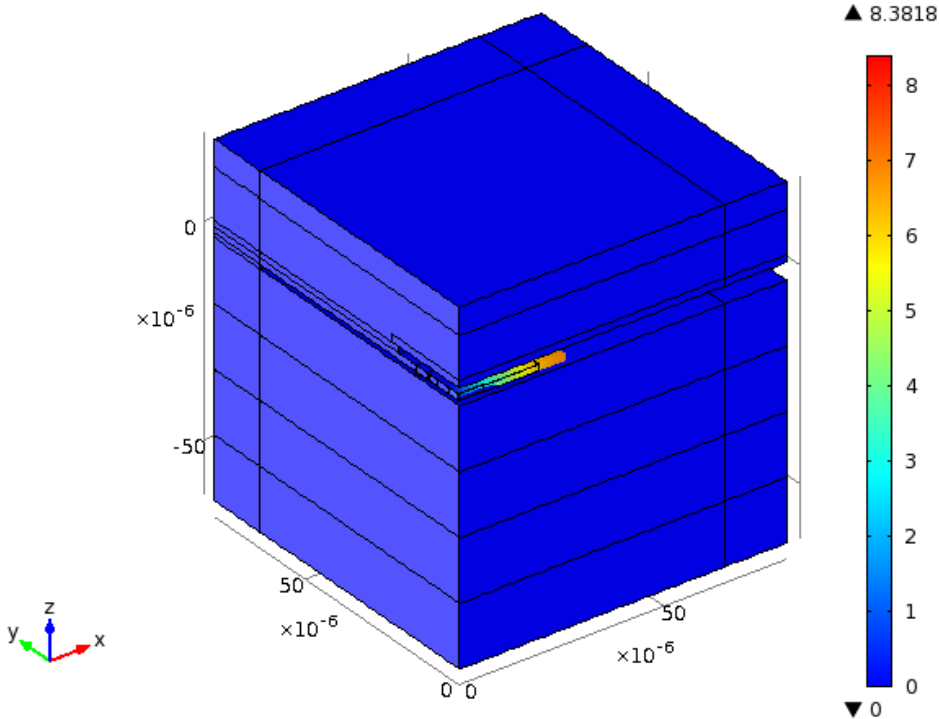


- $Q > 40000$  at appropriate conditions
- Sliding effect on large surface negligible
- Q-factor is slightly dependant on mesh size of the surface where the film damping is applied.

# Overview: Influence of Polyamide Capping above resonator



Surface: Total displacement (m) Surface Deformation: Displacement field (Material)



**Permanent frequency shifts:  $\approx 20$  ppm**  
**Well within specs.**

# Conclusion



- Production steps in CMOS technology have their own influence on the performance of the resonator.
- COMSOL paved the way to better understanding to control specs in production. (Q-factor, dimensions, stress and material loss factors)
- MEMS module was used together with the mechanical module.
  - Prestressed Analysis, eigenfrequency
  - Prestressed Analysis, frequency domain.
  - Heat module, Squeezed film and much more.
- Thanks to Dr. H van de Vlist (NXP, Nijmegen)  
Dr. J. van Beek (NXP, Eindhoven)